



Intelligent Imaging and Analysis

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Message from the Guest Editors

Imaging and analysis is widely involved with various research fields, including biomedical applications, medical imaging and diagnosis, computer vision, autonomous driving and robot controls. Imaging and analysis are now facing a big intelligent change due to the breakthroughs of artificial intelligence techniques, including deep learning.

This Special Issue focuses on the latest developments of learning-based intelligent imaging techniques and subsequent analyses, which include photographic imaging, medical imaging, detection, segmentation, medical diagnosis, computer vision and vision-based robot control. These latest technological developments will be shared through this Special Issue for various researchers who are involved with imaging itself, or using image data and analysis for their own specific purposes. New types of applications utilizing intelligent imaging and analysis techniques are also welcome.

- Photographic imaging
- Medical imaging
- Magnetic resonance imaging
- Computed tomography
- Image reconstruction
- Image detection
- Segmentation
- Diagnosis
- De-noising
- Artifact removal
- Computer vision
- Vision-based robots





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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